



02-18-05

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**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**In re application of: Cécile AULNETTE et al.**

Confirmation No.: 7888

Application No: 10/763,978

Group Art Unit: 2811

Filing Date: January 22, 2004

Examiner:

For: SEMICONDUCTOR STRUCTURE FOR  
PROVIDING STRAINED CRYSTALLINE LAYER ON  
INSULATOR AND METHOD FOR FABRICATING  
SAME

Atty. Docket No.: 4717-7300

## **SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450  
Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a Form PTO-1449 listing ( 1 ) reference for the Examiner's review and consideration. This reference was brought to the attention of the applicant and a copy is enclosed.

It is respectfully requested that this reference be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee is believed to be due for the filing of this statement as it is being submitted prior to an initial office action for this application. Should any fees be required, however, please charge such fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

Date: 2/11/03

Allan A. Fanucci  
Allan A. Fanucci (Reg. No. 30,256)

## Enclosures

<b>LIST OF REFERENCES CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.:	APPLICATION NO.:			
				4717-7300	10/763,978			
				APPLICANT:				
				Cecile AULNETTE et al.				
<b>FILING DATE:</b> January 22, 2004				GROUP:	2811			
<b>U.S. PATENT DOCUMENTS</b>								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA							
	AB							
	AC							
<b>FOREIGN PATENT DOCUMENTS</b>								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
	AD	<b>TW512487 English Abstract</b>	<b>12/2002</b>	<b>Taiwanese</b>			<b>X</b>	
	AE							
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	AF							
	AG							
	AH							
EXAMINER				DATE CONSIDERED				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

